

MOS FIELD EFFECT TRANSISTOR $\mu PA2700TP$

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The μ PA2700TP which has a heat spreader is N-Channel MOS Field Effect Transistor designed for DC/DC converter and power management application of notebook computer.

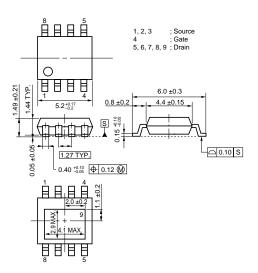
FEATURES

- Low on-state resistance $R_{DS(on)1} = 5.3 \text{ m}\Omega$ MAX. (Vgs = 10 V, ID = 9.0 A) $R_{DS(on)2} = 7.3 \text{ m}\Omega$ MAX. (Vgs = 4.5 V, ID = 9.0 A)
- Low Ciss: Ciss = 2600 pF TYP. (VDS = 10 V, VGS = 0 V)
- Small and surface mount package (Power HSOP8)

ORDERING INFORMATION

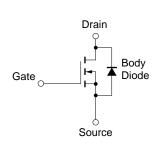
PART NUMBER	PACKAGE
μPA2700TP	Power HSOP8

PACKAGE DRAWING (Unit: mm)



ABSOLUTE MAXIMUM RATINGS (TA = 25°C, Unless otherwise noted, All terminals are connected.)

*	Drain to Source Voltage (Vgs = 0 V)	VDSS	30	V	
	Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V	
	Drain Current (DC) (Tc = 25°C)	ID(DC)1	±42	Α	
	Drain Current (DC) (T _A = 25°C) Note1	I _{D(DC)2}	±20	Α	
	Drain Current (pulse) Note2	I _{D(pulse)}	±120	Α	
	Total Power Dissipation (Tc = 25°C)	P _{T1}	37	W	
	Total Power Dissipation (T _A = 25°C) Note1	P _{T2}	3	W	
	Channel Temperature	Tch	150	°C	
	Storage Temperature	Tstg	-55 to + 150	°C	
	Single Avalanche Current Note3	las	22	Α	
	Single Avalanche Energy Note3	Eas	48.4	mJ	



EQUIVALENT CIRCUIT

- **Notes 1.** Mounted on a glass epoxy board (1 inch x 1 inch x 0.8 mm), PW = 10 sec
 - **2.** PW \leq 10 μ s, Duty Cycle \leq 1%
 - 3. Starting T_{ch} = 25°C, V_{DD} = 15 V, R_G = 25 Ω , L = 100 μ H, V_{GS} = 20 \rightarrow 0 V

Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

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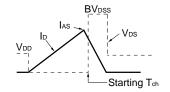


ELECTRICAL CHARACTERISTICS (TA = 25°C, Unless otherwise noted, All terminals are connected.)

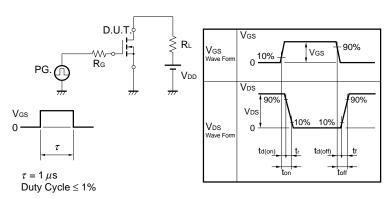
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ioss	V _{DS} = 30 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 9.0 A	11	21.5		S
Drain to Source On-state Resistance	R _{DS(on)1}	VGS = 10 V, ID = 9.0 A		4.2	5.3	mΩ
	R _{DS(on)2}	Vgs = 4.5 V, ID = 9.0 A		5.5	7.3	mΩ
	R _{DS(on)3}	VGS = 4.0 V, ID = 9.0 A		6.3	8.4	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		2600		pF
Output Capacitance	Coss	VGS = 0 V		1000		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		340		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 15 V, I _D = 9.0 A		20		ns
Rise Time	tr	Vgs = 10 V		24		ns
Turn-off Delay Time	t _{d(off)}	R _G = 10 Ω		75		ns
Fall Time	t _f			22		ns
Total Gate Charge	Q _G	V _{DD} = 15 V		26		nC
Gate to Source Charge	Qgs	Vgs = 5 V		7		nC
Gate to Drain Charge	Q _{GD}	I _D = 17 A		11		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 17 A, VGS = 0 V		0.8	1.2	V
Reverse Recovery Time	trr	IF = 17 A, VGS = 0 V		50		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ μs		51		nC

TEST CIRCUIT 1 AVALANCHE CAPABILITY

$V_{GS} = 20 \rightarrow 0 \text{ V}$

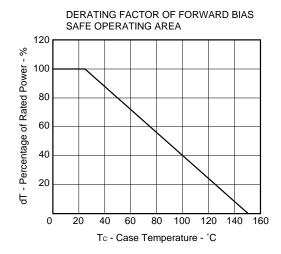


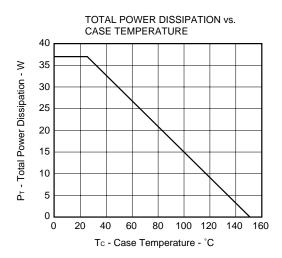
TEST CIRCUIT 2 SWITCHING TIME



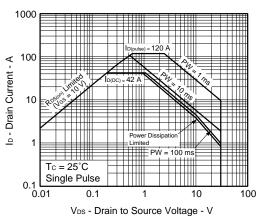
TEST CIRCUIT 3 GATE CHARGE

TYPICAL CHARACTERISTICS (TA = 25°C)



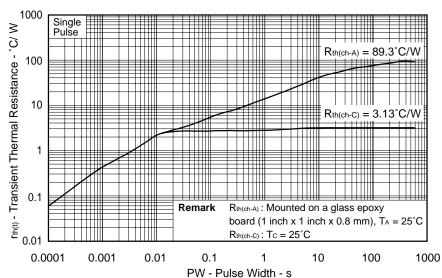


FORWARD BIAS SAFE OPERATING AREA

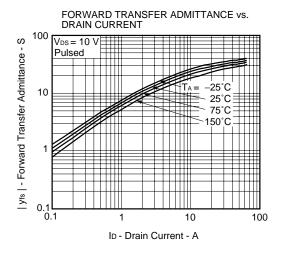


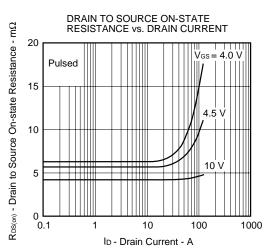
Source voltage - v

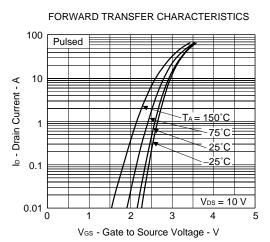
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

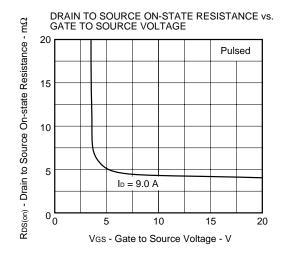


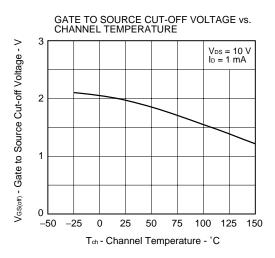
Data Sheet G15851EJ2V0DS 3

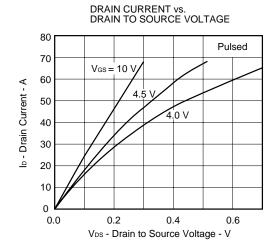


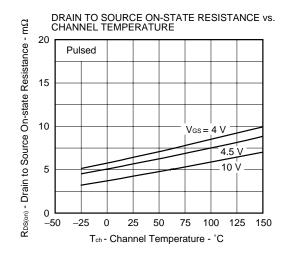


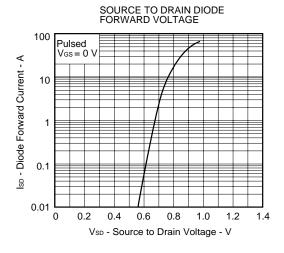


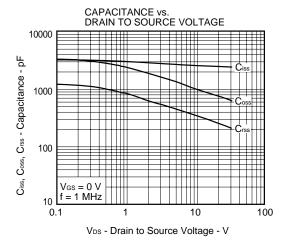


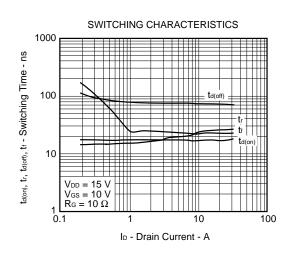


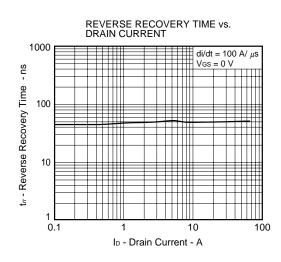


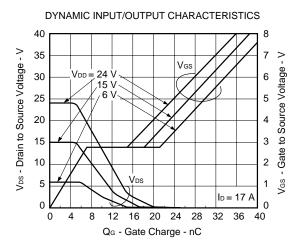












NEC μ PA2700TP

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